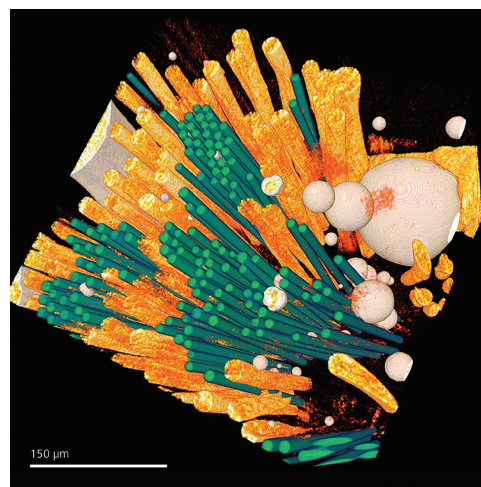
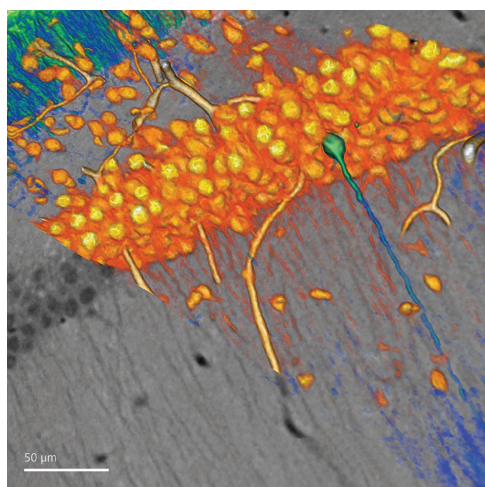


3D X-Ray Microscopy XRM and FIB-SEM: Recent Advances and Results in Materials Research and the Life Sciences

October 26, 10:00 AM
Georgia Institute of Technology
Marcus Nanotechnology Building 1116
345 Ferst Drive NW
Atlanta, GA 30332-1000



Abstract: Join us for a technical seminar on recent advances in instrumentation and methods that have opened the door for a variety of new opportunities in 3D characterization and visualization. Specifically, ZEISS X-Ray microscopes (XRM) have uniquely incorporated synchrotron-influenced optical and detection systems to push the boundaries of laboratory XRM, enabling flexible three dimensional imaging capabilities for a wide variety of applications. Similarly, improvements in FIB-SEM instrumentation have enabled new, high resolution applications spanning from nano-patterning and fabrication to 3D imaging and chemical analysis. This talk will cover an overview of XRM and FIB-SEM technology as well as prominent examples and applications, including correlative workflows.



Register by October the 24th to attend the seminar and receive your lunch at:
ien.gatech.edu/iszeiss



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